

IN THE SPECIFICATION

Please replace the second paragraph on Page 9, lines 13-17, with the following amended paragraph:

-- The detection unit 40 is composed of a spectrograph 42 and a light measuring device array 44. The spectrograph 42 splits the light reflected from the surface of the sample of the substrate 30 based on the ~~degree of each wavelength~~, and the split light is inputted into the optical measuring device array 44, thereby measuring a light intensity at each wavelength. --

Please replace the second paragraph on Page 10, lines 6-10, with the following amended paragraph:

-- Preferably, the measurement of the film thickness performed by the computation unit 52 and the analyzing unit ~~42 54~~ is implemented using a computer. The computer receives a spectrum data with respect to each wavelength from the spectrograph 42 and the light device array 44 and computes the thickness of the thin film and stores a data related to the thickness of the thin film. --